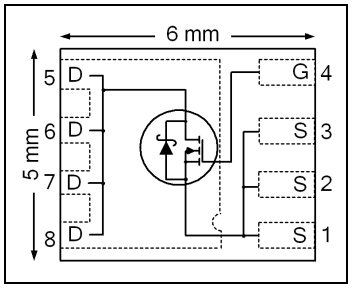
HEXFET® Power MOSFET

V_{DSS}	25	V
$R_{DS(on)}$ max (@ V_{GS} = 10V)	1.35	mΩ
(@ V_{GS} = 4.5V)	1.90	
Q_g (typical)	25	nC
I_D (@$T_{C\ (Bottom)}$ = 25°C)	100⑦	A



PQFN 5X6 mm

Applications

- Synchronous Rectifier MOSFET for Synchronous Buck Converters

Features		Benefits
Low R_{DSon} (<1.35mΩ)		Lower Conduction Losses
Schottky Intrinsic Diode with Low Forward Voltage		Lower Switching Losses
Low Thermal Resistance to PCB (<1.3°C/W)		Enable better thermal dissipation
Low Profile (<0.9 mm)	results in	Increased Power Density
Industry-Standard Pinout	⇒	Multi-Vendor Compatibility
Compatible with Existing Surface Mount Techniques		Easier Manufacturing
RoHS Compliant, Halogen-Free		Environmentally Friendlier
MSL1, Industrial Qualification		Increased Reliability

Base part number	Package Type	Standard Pack		Orderable Part Number
		Form	Quantity	
IRFH4213DPbF	PQFN 5mm x 6 mm	Tape and Reel	4000	IRFH4213DTRPbF

Absolute Maximum Ratings

	Parameter	Max.	Units
V_{GS}	Gate-to-Source Voltage	± 20	V
I_D @ T_A = 25°C	Continuous Drain Current, V_{GS} @ 10V	40	A
I_D @ $T_{C(Bottom)}$ = 25°C	Continuous Drain Current, V_{GS} @ 10V	208⑥⑦	
I_D @ $T_{C(Bottom)}$ = 100°C	Continuous Drain Current, V_{GS} @ 10V	131⑥⑦	
I_D @ $T_{C(Bottom)}$ = 25°C	Continuous Drain Current, V_{GS} @ 10V (Source Bonding Technology Limited)	100⑦	
I_{DM}	Pulsed Drain Current ①	400	
P_D @T_A = 25°C	Power Dissipation ⑤	3.6	W
P_D @$T_{C(Bottom)}$ = 25°C	Power Dissipation	96	
	Linear Derating Factor ⑤	0.029	W/°C
T_J T_{STG}	Operating Junction and Storage Temperature Range	-55 to + 150	°C

Notes ① through ⑥ are on page 8

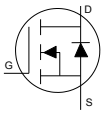
Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	25	—	—	V	V_{GS} = 0V, I_D = 1.0mA
$\Delta BV_{DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	21	—	mV/°C	Reference to 25°C, I_D = 10mA
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	1.10	1.35	mΩ	V_{GS} = 10V, I_D = 50A ③
		—	1.50	1.90		V_{GS} = 4.5V, I_D = 50A ③
$V_{GS(th)}$	Gate Threshold Voltage	1.1	1.6	2.1	V	V_{DS} = V_{GS}, I_D = 100µA
$\Delta V_{GS(th)}$	Gate Threshold Voltage Coefficient	—	-4.5	—	mV/°C	V_{DS} = V_{GS}, I_D = 10mA
I_{DSS}	Drain-to-Source Leakage Current	—	—	250	µA	V_{DS} = 20V, V_{GS} = 0V
I_{GSS}	Gate-to-Source Forward Leakage	—	—	100	nA	V_{GS} = 20V
	Gate-to-Source Reverse Leakage	—	—	-100		V_{GS} = -20V
gfs	Forward Transconductance	340	—	—	S	V_{DS} = 10V, I_D = 50A
Q_g	Total Gate Charge	—	55	—	nC	V_{GS} = 10V, V_{DS} = 13V, I_D = 50A
Q_g	Total Gate Charge	—	25	38	nC	V_{DS} = 13V V_{GS} = 4.5V I_D = 50A
Q_{gs1}	Pre-Vth Gate-to-Source Charge	—	9.4	—		
Q_{gs2}	Post-Vth Gate-to-Source Charge	—	4.1	—		
Q_{gd}	Gate-to-Drain Charge	—	9.4	—		
Q_{godr}	Gate Charge Overdrive	—	2.1	—		
Q_{sw}	Switch Charge (Q_{gs2} + Q_{gd})	—	13.5	—		
Q_{oss}	Output Charge	—	27	—	nC	V_{DS} = 16V, V_{GS} = 0V
R_G	Gate Resistance	—	1.5	—	Ω	
$t_{d(on)}$	Turn-On Delay Time	—	14	—	ns	V_{DD} = 13V, V_{GS} = 4.5V I_D = 50A R_G=2.0Ω
t_r	Rise Time	—	30	—		
$t_{d(off)}$	Turn-Off Delay Time	—	18	—		
t_f	Fall Time	—	12	—		
C_{iss}	Input Capacitance	—	3520	—	pF	V_{GS} = 0V V_{DS} = 13V f = 1.0MHz
C_{oss}	Output Capacitance	—	1070	—		
C_{rss}	Reverse Transfer Capacitance	—	250	—		

Avalanche Characteristics

	Parameter	Typ.	Max.
E_{AS}	Single Pulse Avalanche Energy ②	—	180
I_{AR}	Avalanche Current ①	—	50

Diode Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	100⑦	A	MOSFET symbol showing the integral reverse p-n junction diode. 
I_{SM}	Pulsed Source Current (Body Diode) ①	—	—	400		
V_{SD}	Diode Forward Voltage	—	—	0.8	V	T_J = 25°C, I_S = 50A, V_{GS} = 0V ③
t_{rr}	Reverse Recovery Time	—	26	37	ns	T_J = 25°C, I_F = 50A, V_{DD} = 13V
Q_{rr}	Reverse Recovery Charge	—	35	53	nC	di/dt = 260A/µs ③

Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{\theta JC}$ (Bottom)	Junction-to-Case ④	—	1.3	°C/W
$R_{\theta JC}$ (Top)	Junction-to-Case ④	—	21	
$R_{\theta JA}$	Junction-to-Ambient ⑤	—	35	
$R_{\theta JA}$ (<10s)	Junction-to-Ambient ⑤	—	21	

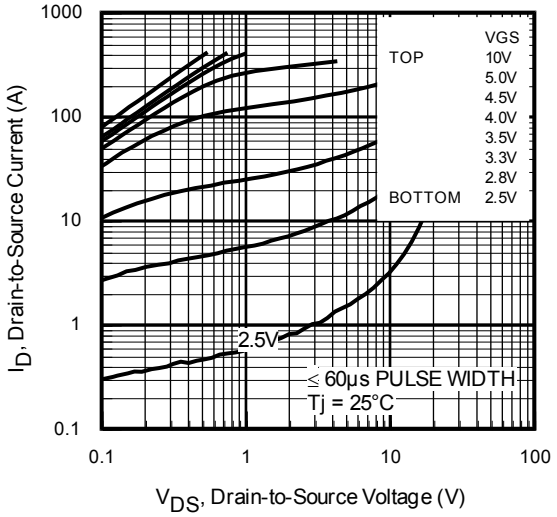


Fig 1. Typical Output Characteristics

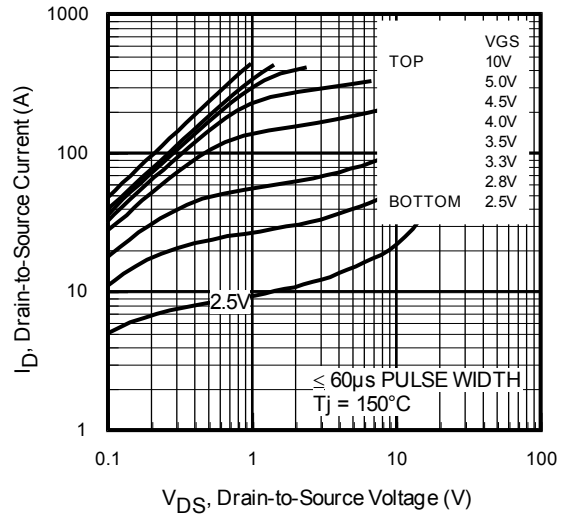


Fig 2. Typical Output Characteristics

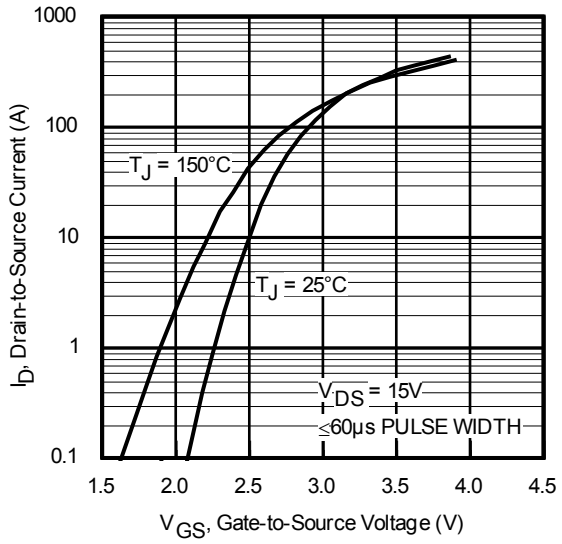


Fig 3. Typical Transfer Characteristics

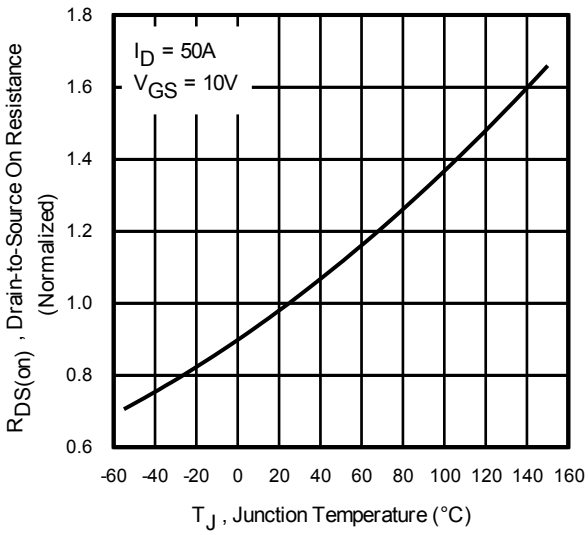


Fig 4. Normalized On-Resistance vs. Temperature

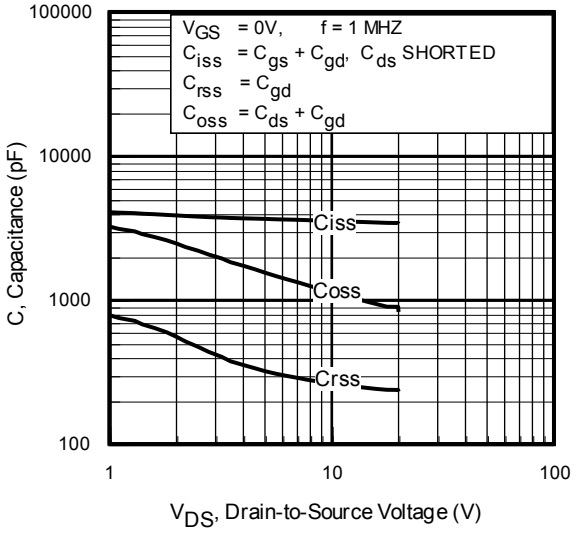


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

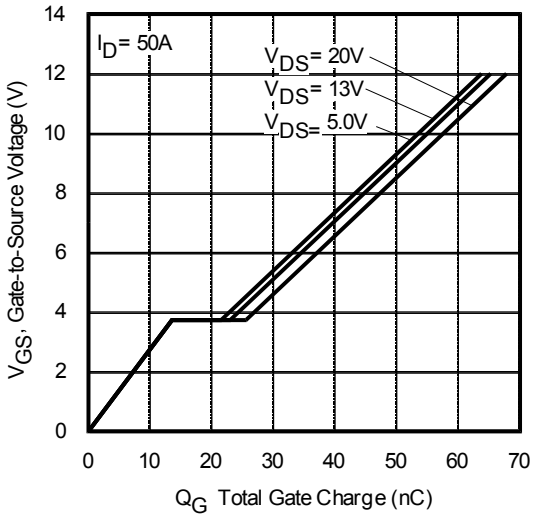


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

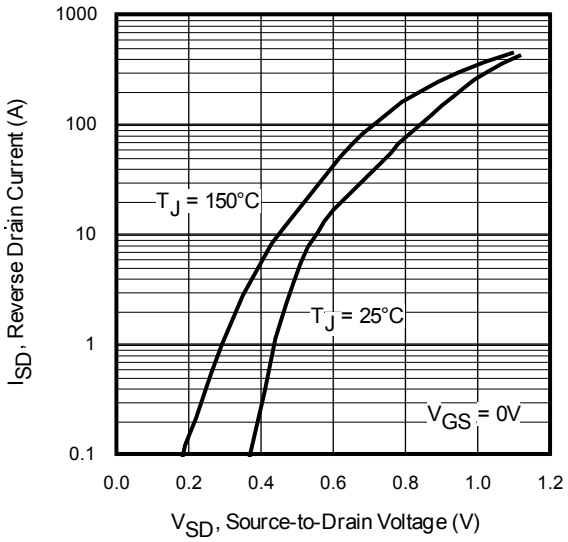


Fig 7. Typical Source-Drain Diode Forward Voltage

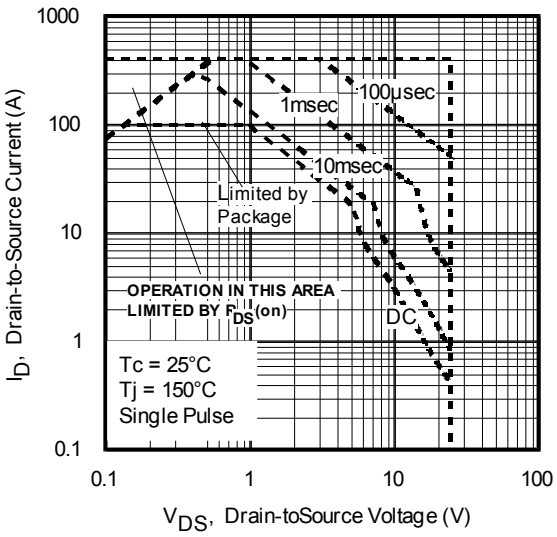


Fig 8. Maximum Safe Operating Area

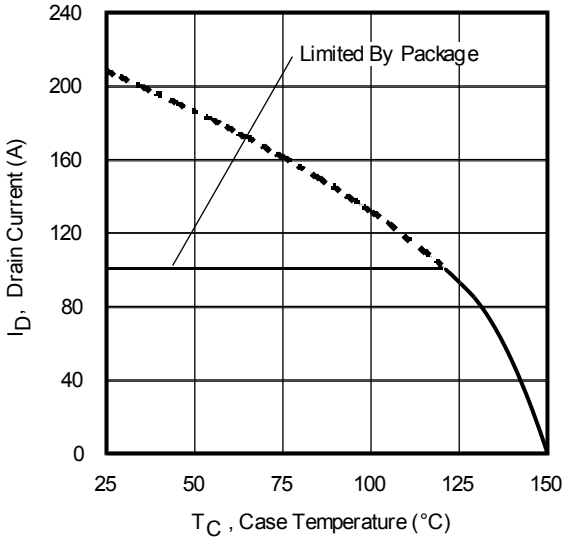


Fig 9. Maximum Drain Current vs. Case Temperature

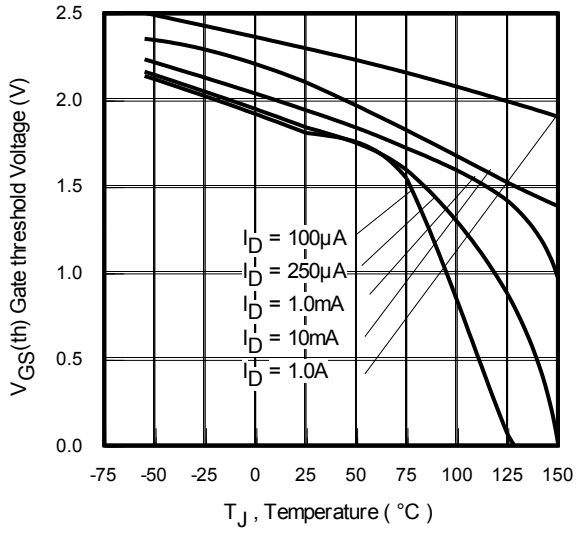


Fig 10. Threshold Voltage Vs. Temperature

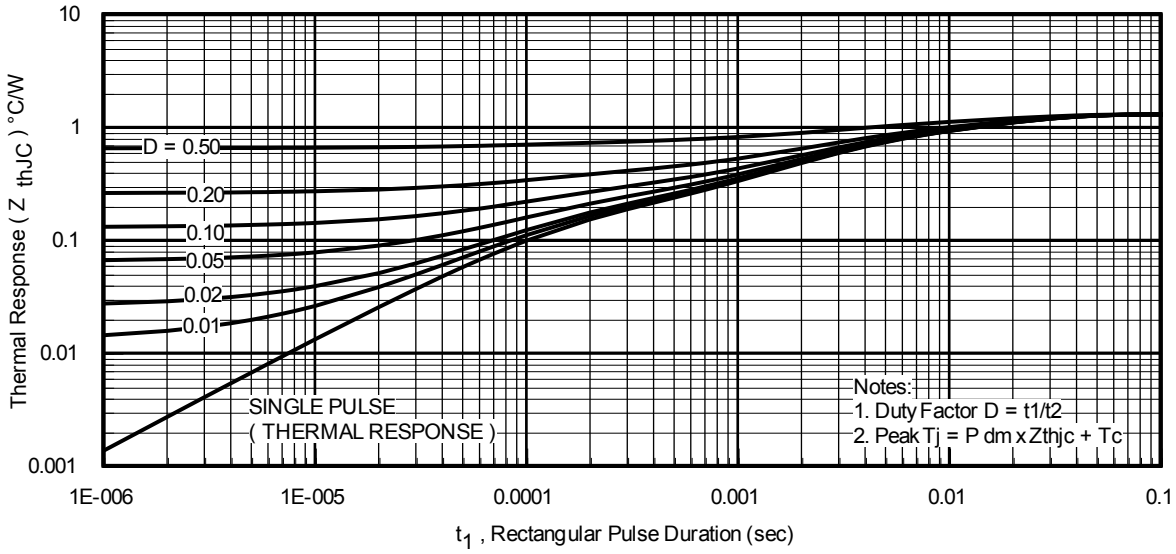


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

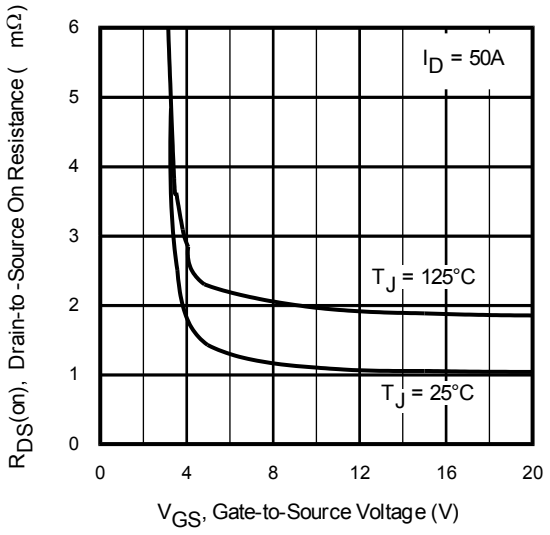


Fig 12. On– Resistance vs. Gate Voltage

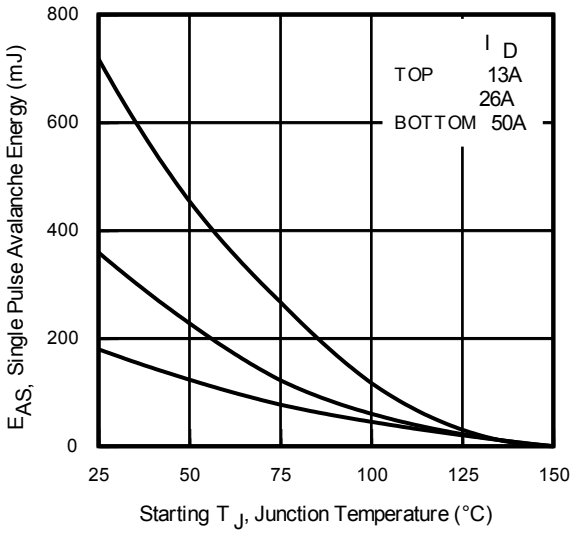


Fig 13. Maximum Avalanche Energy vs. Drain Current

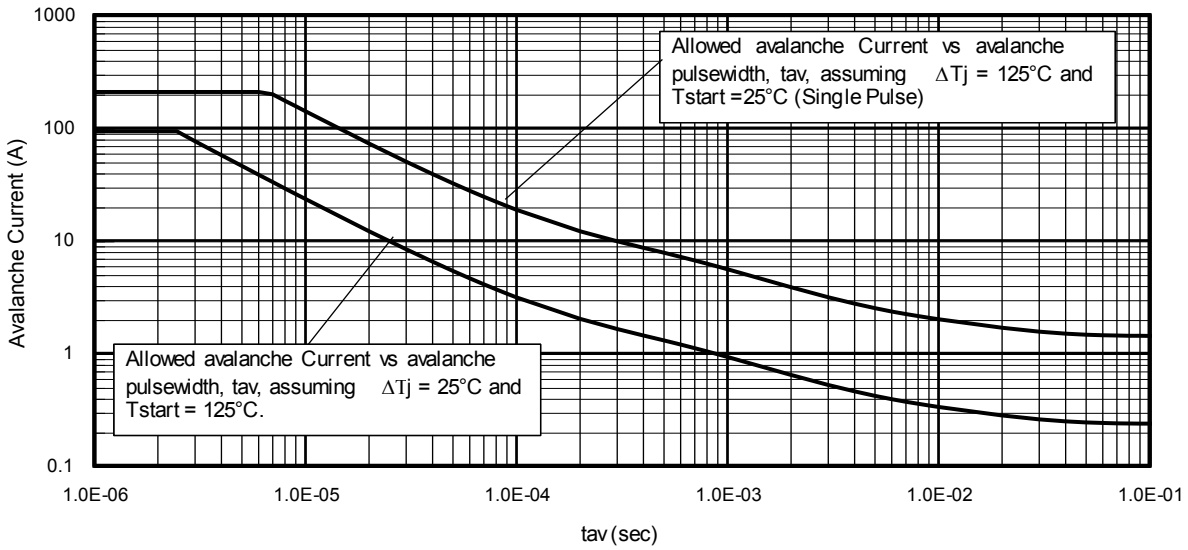


Fig 14. Typical Avalanche Current vs. Pulsewidth

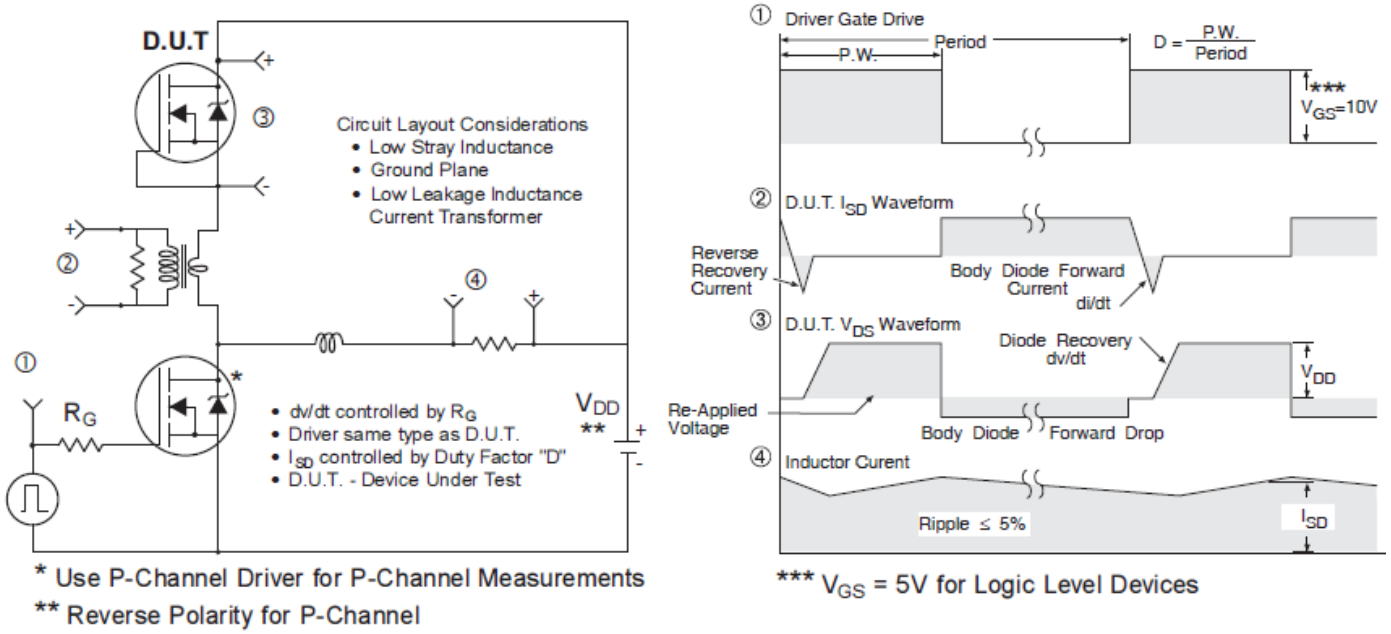


Fig 15. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

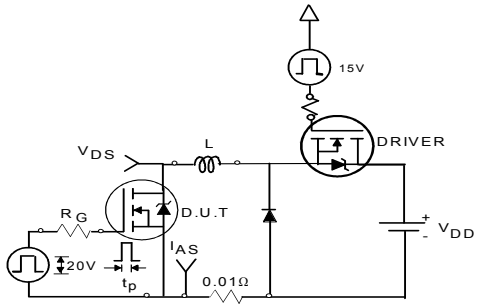


Fig 16a. Unclamped Inductive Test Circuit

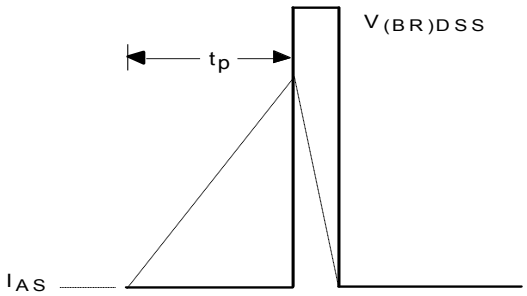


Fig 16b. Unclamped Inductive Waveforms

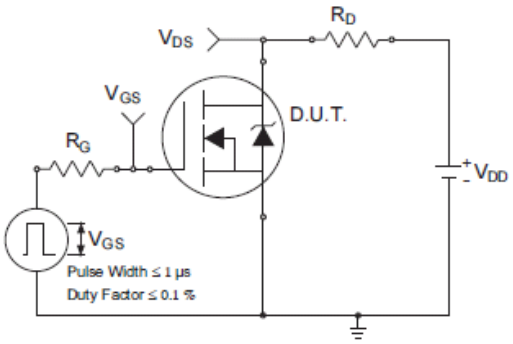


Fig 17a. Switching Time Test Circuit

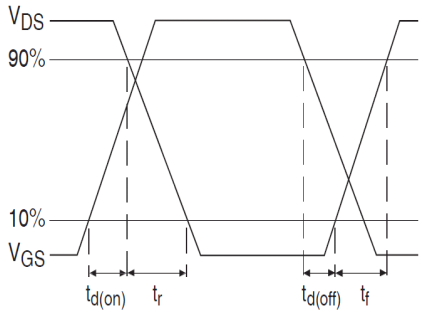


Fig 17b. Switching Time Waveforms

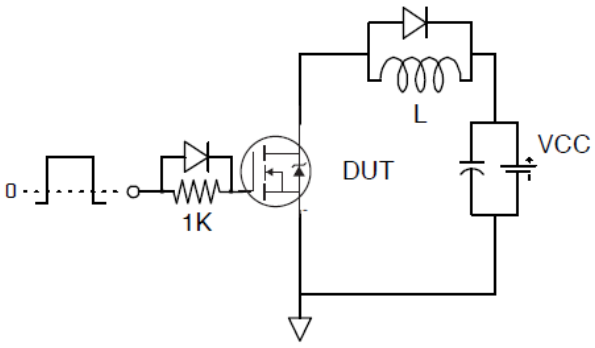


Fig 18. Gate Charge Test Circuit

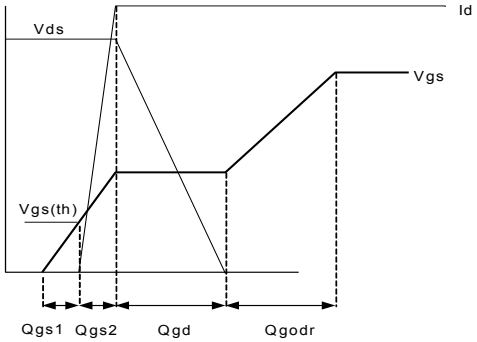
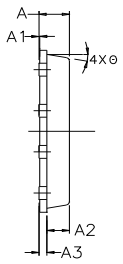
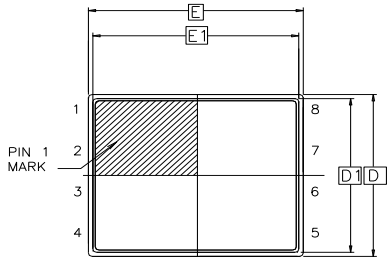


Fig 19. Gate Charge Waveform

PQFN 5x6 Outline "B" Package Details

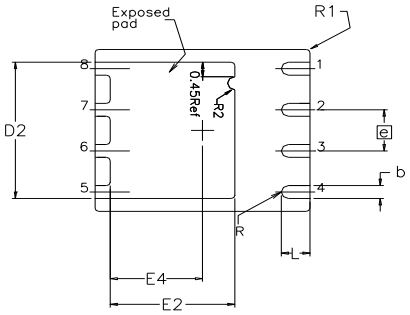


SIDE VIEW



TOP VIEW

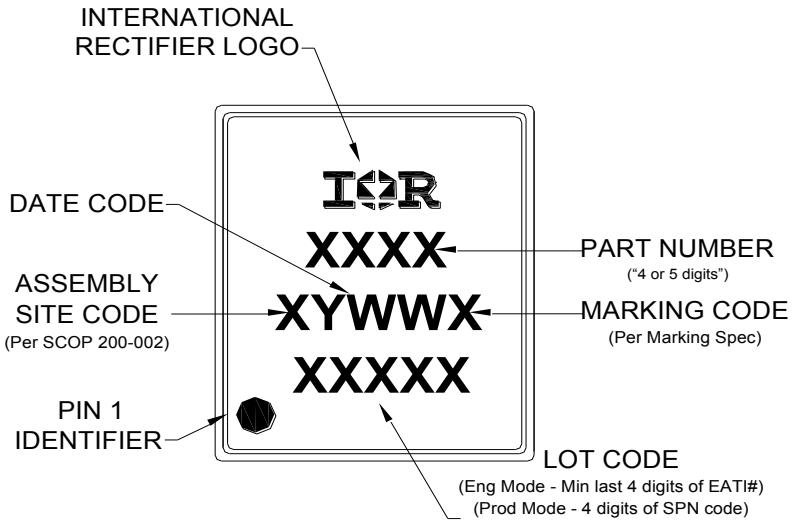
DIM / SYMBOL	MIN	NOM	MAX
A	0.800	0.830	1.05
A1	0.000	0.020	0.050
A2	0.580	0.630	0.680
A3		0.254 REF	
Θ	0°	10°	12°
b	0.350	0.400	0.470
D	4.850	5.000	5.150
D1	4.675	4.750	5.000
D2	3.700	4.210	4.300
e		1.270 BSC	
E	5.850	6.000	6.150
E1	5.675	5.750	6.000
E2	3.380	3.480	3.760
E4	2.480	2.580	2.680
L	0.550	0.800	0.900
R		0.200 REF	
R1		0.100 REF	
R2	0.150	0.200	0.250



BOTTOM VIEW

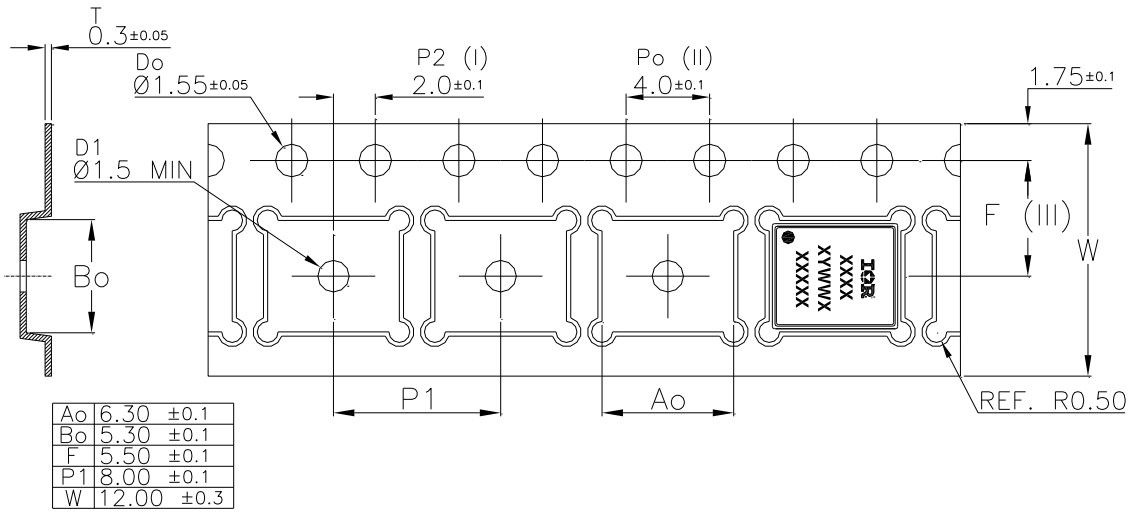
For more information on board mounting, including footprint and stencil recommendation, please refer to application note AN-1136: http://www.irf.com/technical-info/appnotes/an-1136.pdf
For more information on package inspection techniques, please refer to application note AN-1154: http://www.irf.com/technical-info/appnotes/an-1154.pdf

PQFN 5x6 Outline "B" Part Marking



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

PQFN 5x6 Outline "B" Tape and Reel



Ao	6.30	±0.1
Bo	5.30	±0.1
F	5.50	±0.1
P1	8.00	±0.1
W	12.00	±0.3

Qualification Information†

Qualification Level	Industrial (per JEDEC JESD47F†† guidelines)	
Moisture Sensitivity Level	PQFN 5mm x 6mm	MSL1 (per JEDEC J-STD-020D††)
RoHS Compliant	Yes	

† Qualification standards can be found at International Rectifier's web site: http://www.irf.com/product-info/reliability

†† Applicable version of JEDEC standard at the time of product release.

Notes:

① Repetitive rating; pulse width limited by max. junction temperature.

② Starting T_J = 25°C, L = 0.107mH, R_G = 50Ω, I_{AS} = 50A.

③ Pulse width ≤ 400µs; duty cycle ≤ 2%.

④ R_θ is measured at T_J of approximately 90°C.

⑤ When mounted on 1 inch square PCB (FR-4). Please refer to AN-994 for more details: http://www.irf.com/technical-info/appnotes/an-994.pdf

⑥ Calculated continuous current based on maximum allowable junction temperature.

⑦ Current is limited to 100A by source bonding technology.

Revision History

Date	Comments
05/20/2013	• Updated package 3D drawing, on page 1. • Added Continuous Drain Current limited by source bonding technology, on page 1. • Divided note 6 into note 6 & 7, on page 8.
04/10/2013	• Release of final data sheet.

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